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**AEHR TEST SYSTEMS RECEIVES MTX ORDERS FROM
NANYA'S TEST AND ASSEMBLY SUBCONTRACTORS**

Fremont, CA (February 13, 2003) – Aehr Test Systems (Nasdaq: AEHR), a leading supplier of test and burn-in equipment to semiconductor manufacturers, today announced that two leading Taiwanese test and assembly subcontractors for Nanya Technology Corporation have purchased multiple MTX systems totaling over \$2 million. The systems are scheduled to ship in the first half of calendar 2003.

C.J. Meurell, president and chief operating officer of Aehr Test, said, “The subcontractors recently bought these follow-on MTX systems to meet Nanya’s 256Mb DDR memory capacity ramp. We believe that these repeat orders of the MTX prove that our customers understand that they can count on the burn-in and test technology of this system to meet the requirements of present and future generations of memory devices.”

The MTX Massively Parallel Test System is designed to reduce the cost of testing the latest generation of high performance memories by burning-in and functionally testing more than 10,000 memory devices simultaneously. The test results using MTX systems have correlated extremely well with the test results of expensive high-speed testers. This allows manufacturers to offload up to 70% of the test time traditionally performed on high-speed testers, freeing the testers for the parametric tests and high-speed sorting that require their costly high performance features.

Bill Barraclough, director of product marketing at Aehr Test, said, “Most of the burn-in and test systems purchased were the new MTX-Rp. The Rp version of the MTX targets production test and burn-in of next generation DDR devices. This production system maintains compatibility with the MTX-R, while offering a lower burn-in and test cost per device.”

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a leading world-wide provider of systems for burning-in and testing DRAM and logic integrated circuits and has an installed base of more than 2,000 systems worldwide. Aehr Test has developed and introduced several innovative products, including the FOX™, MTX, MAX3 and MAX4 systems and the DiePak® carrier. The FOX system is a full wafer contact burn-in and test system. The MTX system is a massively parallel test system designed to reduce the cost of memory testing by performing both

test and burn-in on thousands of devices simultaneously. The MAX system can effectively burn-in and functionally test sophisticated devices, such as digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die.

Safe Harbor Statement

This release contains forward-looking statements that involve risks and uncertainties relating to projections regarding industry growth and customer demand for Aehr Test's products. Actual results may vary from projected results. These risks and uncertainties include economic conditions in Asia and elsewhere, world events, acceptance by customers of the FOX, MTX, MAX and DiePak technologies, the ability of the Company to gain business in China, the Company's development and manufacture of a commercially successful wafer-level burn-in system, and the potential emergence of alternative technologies, which could adversely affect demand for Aehr Test's products in calendar year 2003. See Aehr Test's recent 10-K and 10-Q reports filed with the SEC for additional risks affecting Aehr Test.

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